ELECTRICAL SPECIFICATIONS

| Nominal Frequency | 16.384 MHz |
| :---: | :---: |
| Frequency Tolerance/Stability | $\pm 50 \mathrm{ppm}$ Maximum (Inclusive of all conditions: Calibration Tolerance at $25^{\circ} \mathrm{C}$, Frequency Stability over the Operating Temperature Range,Supply Voltage Change, Output Load Change, <br> First Year Aging at $25^{\circ} \mathrm{C}$, Shock, and Vibration) |
| Aging at $25^{\circ} \mathrm{C}$ | $\pm 5 \mathrm{ppm} / \mathrm{year}$ Maximum |
| Operating Temperature Range | $-20^{\circ} \mathrm{C}$ to $+70^{\circ} \mathrm{C}$ |
| Supply Voltage | $5.0 \mathrm{Vdc} \pm 10 \%$ |
| Input Current | 45mA Maximum (Unloaded) |
| Output Voltage Logic High (Voh) | Vdd-0.4Vdc Minimum ( $\mathrm{IOH}=-16 \mathrm{~mA}$ ) |
| Output Voltage Logic Low (Vol) | 0.4 Vdc Maximum ( $\mathrm{IOL}=+16 \mathrm{~mA}$ ) |
| Rise/Fall Time | 4 nSec Maximum (Measured at 20\% to 80\% of waveform) |
| Duty Cycle | $50 \pm 10(\%)$ (Measured at 1.4 Vdc with TTL Load; Measured at $50 \%$ of waveform with HCMOS Load) |
| Load Drive Capability | 50pF HCMOS Load Maximum |
| Output Logic Type | CMOS |
| Pin 1 Connection | Tri-State (Disabled Output: High Impedance) |
| Tri-State Input Voltage (Vih and Vil) | +2.0Vdc Minimum to enable output, +0.8 Vdc Max, to disable output, No Connect to enable output. |
| Standby Current | $50 \mu \mathrm{~A}$ Maximum (Pin 1 = Ground) |
| Disable Current | 30mA Maximum (Pin 1 = Ground) |
| Absolute Clock Jitter | $\pm 250$ pSec Maximum, $\pm 100 \mathrm{pSec}$ Typical |
| One Sigma Clock Period Jitter | $\pm 50 \mathrm{pSec}$ Maximum |
| Start Up Time | 10 mSec Maximum |
| Storage Temperature Range | $-55^{\circ} \mathrm{C}$ to $+125^{\circ} \mathrm{C}$ |

ENVIRONMENTAL \& MECHANICAL SPECIFICATIONS

| Fine Leak Test | MIL-STD-883, Method 1014, Condition A |
| :--- | :--- |
| Gross Leak Test | MIL-STD-883, Method 1014, Condition C |
| Mechanical Shock | MIL-STD-202, Method 213, Condition C |
| Resistance to Soldering Heat | MIL-STD-202, Method 210 |
| Resistance to Solvents | MIL-STD-202, Method 215 |
| Solderability | MIL-STD-883, Method 2003 |
| Temperature Cycling | MIL-STD-883, Method 1010 |
| Vibration | MIL-STD-883, Method 2007, Condition A |

MECHANICAL DIMENSIONS (all dimensions in millimeters)



| LINE |  |
| :--- | :--- | MARKING

## Suggested Solder Pad Layout

All Dimensions in Millimeters


All Tolerances are $\pm 0.1$

## OUTPUT WAVEFORM \& TIMING DIAGRAM



## Test Circuit for TTL Output

| Output Load <br> Drive Capability | $\mathbf{R}_{\mathbf{L}}$ Value <br> (Ohms) | $\mathbf{C}_{\mathbf{L}}$ Value <br> $(\mathbf{p F})$ |
| :---: | :---: | :---: |
| 10 TTL | 390 | 15 |
| 5 TTL | 780 | 15 |
| 2 TTL | 1100 | 6 |
| 10 LSTTL | 2000 | 15 |
| 1 TTL | 2200 | 3 |

Table 1: $R_{L}$ Resistance Value and $C_{L}$ Capacitance Value Vs. Output Load Drive Capability


Note 1: An external $0.1 \mu \mathrm{~F}$ low frequency tantalum bypass capacitor in parallel with a $0.01 \mu \mathrm{~F}$ high frequency ceramic bypass capacitor close to the package ground and $\mathrm{V}_{\mathrm{DD}}$ pin is required.
Note 2: A low capacitance ( <12pF), 10X attenuation factor, high impedance ( $>10 \mathrm{Mohms}$ ), and high bandwidth ( $>300 \mathrm{MHz}$ ) passive probe is recommended.
Note 3: Capacitance value $C_{L}$ includes sum of all probe and fixture capacitance.
Note 4: Resistance value $R_{L}$ is shown in Table 1. See applicable specification sheet for 'Load Drive Capability'.
Note 5: All diodes are MMBD7000, MMBD914, or equivalent.

## Test Circuit for CMOS Output



Note 1: An external $0.1 \mu \mathrm{~F}$ low frequency tantalum bypass capacitor in parallel with a $0.01 \mu \mathrm{~F}$ high frequency ceramic bypass capacitor close to the package ground and $V_{D D}$ pin is required.
Note 2: A low capacitance ( $<12 \mathrm{pF}$ ), 10X attenuation factor, high impedance ( $>10 \mathrm{Mohms}$ ), and high bandwidth ( $>300 \mathrm{MHz}$ ) passive probe is recommended.
Note 3: Capacitance value $\mathrm{C}_{\mathrm{L}}$ includes sum of all probe and fixture capacitance.

## EP1445SJTSC-16.384M

## Recommended Solder Reflow Methods



Low Temperature Infrared/Convection $240^{\circ} \mathrm{C}$

| $\mathrm{T}_{\mathrm{S}}$ MAX to $\mathrm{T}_{\mathrm{L}}$ (Ramp-up Rate) | $5^{\circ} \mathrm{C} /$ second Maximum |
| :---: | :---: |
| Preheat |  |
| - Temperature Minimum ( $\mathrm{T}_{\mathrm{s}} \mathrm{MIN}$ ) | N/A |
| - Temperature Typical (Ts TYP) | $150^{\circ} \mathrm{C}$ |
| - Temperature Maximum (Ts MAX) | N/A |
| - Time (ts MIN) | 60-120 Seconds |
| Ramp-up Rate ( $\mathrm{L}_{\mathrm{L}}$ to $\mathrm{T}_{\mathrm{P}}$ ) | $5^{\circ} \mathrm{C} /$ second Maximum |
| Time Maintained Above: |  |
| - Temperature ( $\mathrm{T}_{\mathrm{L}}$ ) | $150^{\circ} \mathrm{C}$ |
| - Time ( $\mathrm{t}_{\mathrm{L}}$ ) | 200 Seconds Maximum |
| Peak Temperature ( $\mathrm{T}_{\mathrm{P}}$ ) | $240^{\circ} \mathrm{C}$ Maximum |
| Target Peak Temperature ( $\mathrm{T}_{\mathrm{P}}$ Target) | $240^{\circ} \mathrm{C}$ Maximum 1 Time / $230^{\circ} \mathrm{C}$ Maximum 2 Times |
| Time within $5^{\circ} \mathrm{C}$ of actual peak ( $\mathrm{t}_{\mathrm{p}}$ ) | 10 seconds Maximum 2 Times / 80 seconds Maximum 1 Time |
| Ramp-down Rate | $5^{\circ} \mathrm{C} /$ second Maximum |
| Time $25^{\circ} \mathrm{C}$ to Peak Temperature (t) | N/A |
| Moisture Sensitivity Level | Level 1 |

## Low Temperature Manual Soldering

$185^{\circ} \mathrm{C}$ Maximum for 10 seconds Maximum, 2 times Maximum.
High Temperature Manual Soldering
$260^{\circ} \mathrm{C}$ Maximum for 5 seconds Maximum, 2 times Maximum.

